

**Product Features**

- Maximum rated frequency: 133 MHz
- Low cycle-to-cycle jitter
- Input to output delay, less than 200ps
- External feedback pin allows outputs to be synchronized to the clock input
- 5V tolerant input\*
- Operates at 3.3V V<sub>DD</sub>
- Test mode allows bypass of the PLL for system testing purposes (e.g., IBIS measurements)
- Clock frequency multipliers ½x to 4x dependent on option
- Space-saving Packages:  
16-pin, 150-mil SOIC (W)  
16-pin 173-mil TSSOP (L)

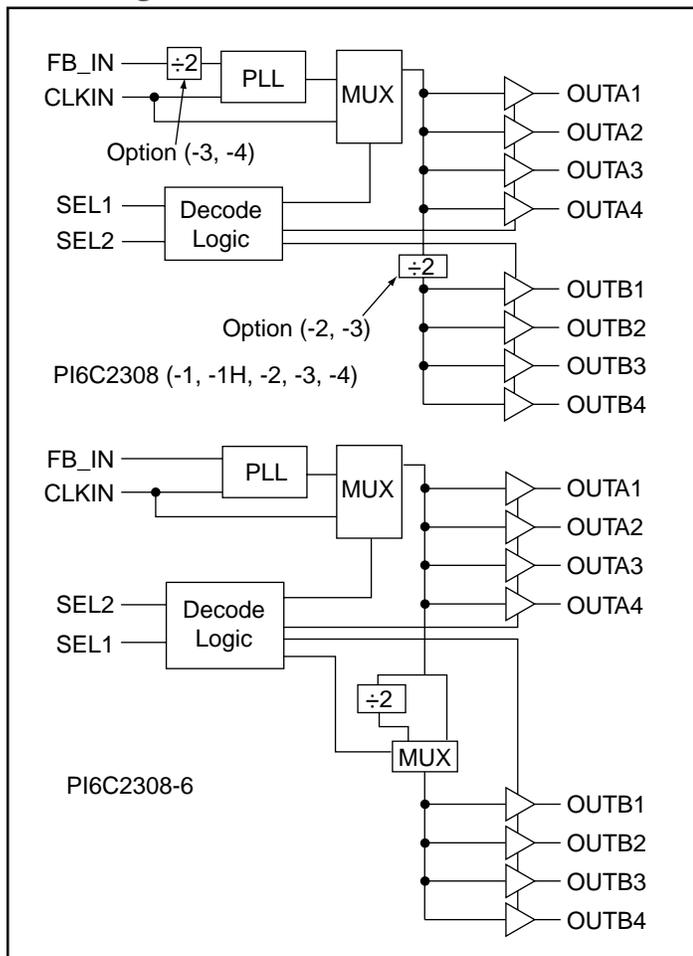
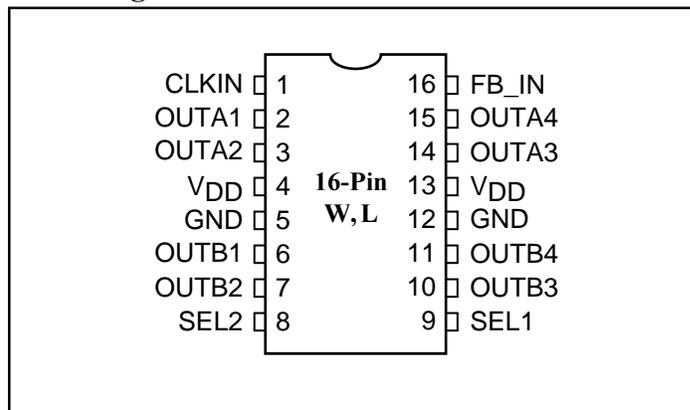
\* *FB\_IN and CLKIN must reference the same voltage thresholds for the PLL to deliver zero delay skewing*

**Functional Description**

The PI6C2308 is a PLL-based, zero-delay buffer, with the ability to distribute eight outputs of up to 133 MHz at 3.3 V. Two banks of four outputs exist, and, depending on product option ordered, can supply either reference frequency, prescaled half frequency, or multiplied 2x or 4x input clock frequencies. The PI6C2308 family has a power-sparing feature: when input SEL2 is 0, the component will 3-state one or both banks of outputs depending on the state of input SEL1. A PLL bypass test mode also exists. This product line is available in high-drive and industrial environment versions.

An external feedback pin is used to synchronize the outputs to the input; the relationship between loading of this signal and the other outputs determines the input-output delay.

The PI6C2308 is characterized for both commercial and industrial operation.

**Block Diagram**

**Pin Configuration PI6C2308**


**Input Select Decoding for PI6C2308 (-1, -1H,-4)**

SEL2	SEL1	OUTA [1-4]	OUTB [1-4]	Output Source	PLL
0	0	3-State	3-State	PLL	OFF
0	1	PLL	3-State	PLL	ON
1	0	CLKIN	CLKIN	CLKIN	OFF
1	1	PLL	PLL	PLL	ON

**Input Select Decoding for PI6C2308 (-2,-3)**

SEL2	SEL1	OUTA [1-4]	OUTB [1-4]	Output Source	PLL
0	0	3-State	3-State	PLL	OFF
0	1	PLL	3-State	PLL	ON
1	0	CLKIN	CLKIN/2	CLKIN	OFF
1	1	PLL	PLL	PLL	ON

**Input Select Decoding for PI6C2308-6**

SEL2	SEL1	OUTA [1-4]	OUTB [1-4]	Output Source	PLL
0	0	3-State	3-State	PLL	OFF
0	1	CLKIN	CLKIN/2	CLKIN	OFF
1	0	PLL	PLL	PLL	ON
1	1	PLL	PLL/2	PLL	ON

**PI6C2308 Configurations**

Device	Feedback From	OUTA [1-4] Frequency	OUTB [1-4] Frequency
PI6C2308-1	OUTA or OUTB	CLKIN	CLKIN
PI6C2308-1H	OUTA or OUTB	CLKIN	CLKIN
PI6C2308-2	OUTA	CLKIN	CLKIN/2
PI6C2308-2	OUTB	2X CLKIN	CLKIN
PI6C2308-3	OUTA	2X CLKIN	CLKIN or $\overline{\text{CLKIN}}^{(1)}$
PI6C2308-3	OUTB	4X CLKIN	2X CLKIN
PI6C2308-4	OUTA or OUTB	2X CLKIN	2X CLKIN
PI6C2308-6	OUTA	CLKIN	CLKIN or CLKIN/2
PI6C2308-6	OUTB	CLKIN or 2X CLKIN	CLKIN

**Note:**

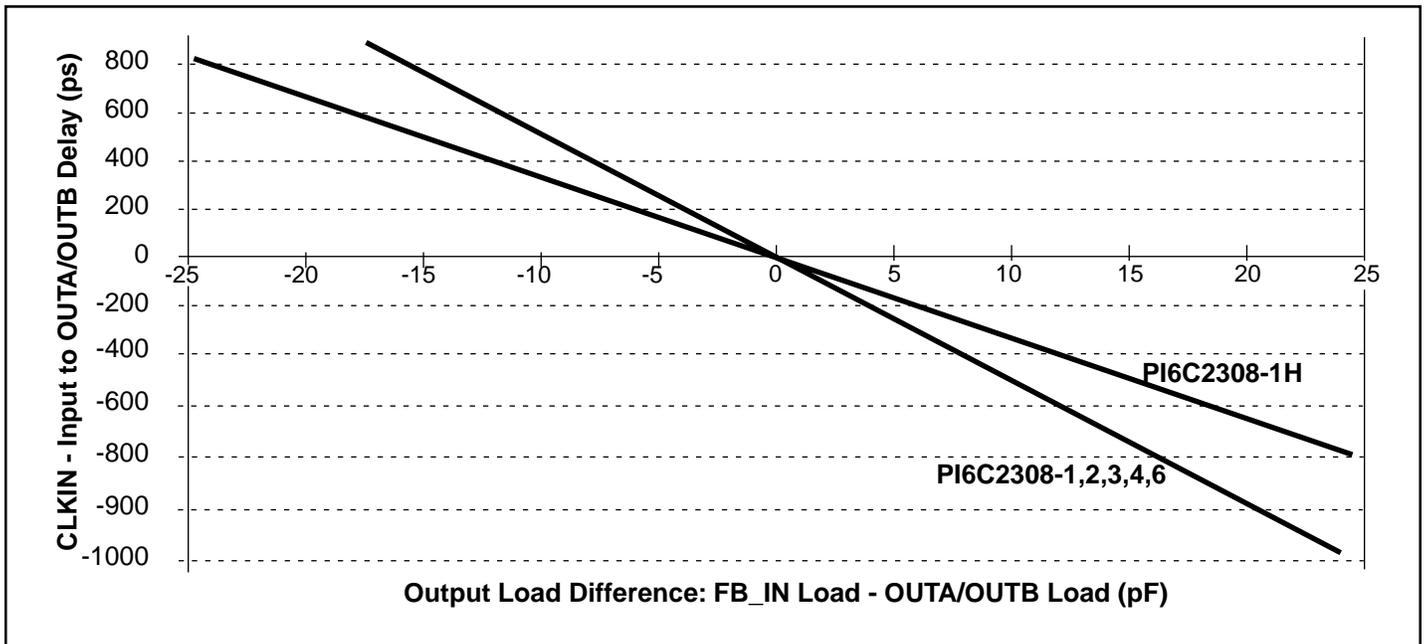
1. Output phase is indeterminant (0° or 180° from CLKIN)

**Pin Description**

Pin	Signal	Description
1	CLKIN	Input clock reference frequency (weak pull-down)
2, 3, 14, 15	OUTA[1-4]	Clock output, Bank A (weak pull-down)
4, 13	V <sub>DD</sub>	3.3V supply
5, 12	GND	Ground
6, 7, 10, 11	OUTB[1-4]	Clock output, Bank B (weak pull-down)
8	SEL2	Select input, bit 2 (weak pull-up)
9	SEL1	Select input, bit 1 (weak pull-up)
16	FB_IN	PLL feedback input

**Zero Delay and Skew Control**

**CLKIN Input to Output Bank Delay vs. Difference in Loading between FB\_IN pin and OUTA/OUTB pins**



The relationship between loading of the FB\_IN signal and other outputs determines the input-output delay. Zero delay is achieved when all outputs, including feedback, are loaded equally.

**Maximum Ratings**

Supply Voltage to Ground Potential .....	-0.5V to +7.0V
DC Input Voltage (Except CLKIN) .....	-0.5V to V <sub>DD</sub> +0.5V
DC Input Voltage CLKIN .....	-0.5 to 7V
Storage Temperature .....	-65°C to +150°C
Maximum Soldering Temperature (10 seconds) .....	260°C
Junction Temperature .....	150°C
Static Discharge Voltage (per MIL-STD-883, Method 3015) .....	>2000V

**Operating Conditions** ( $V_{CC}=3.3V\pm 0.3V$ )

Parameter	Description	Min.	Max.	Units
$V_{DD}$	Supply Voltage	3.0	3.6	V
$T_A$	Commerical Operating Temperature	0	70	°C
	Industrial Operating Temperature	-40	85	
$C_L$	Load Capacitance, below 100 MHz	—	30	pF
	Load Capacitance, from 100 MHz to 133 MHz	—	15	
$C_{IN}$	Input Capacitance	—	7	

**DC Electrical Characteristics for Industrial Temperature Devices**

Parameter	Description	Test Conditions	Min.	Max.	Units
$V_{IL}$	Input LOW Voltage			0.8	V
$V_{IH}$	Input HIGH Voltage		2.0		
$I_{IL}$	Input LOW Current	$V_{IN} = 0V$		50.0	μA
$I_{IH}$	Input HIGH Current	$V_{IN} = V_{DD}$		100.0	
$V_{OL}$	Output LOW Voltage	$I_{OL} = 8mA (-1, -2, -3, -4, -6); I_{OL} = 12mA (-1H)$		0.4	V
$V_{OH}$	Output HIGH Voltage	$I_{OH} = -8mA (-1, -2, -3, -4, -6); I_{OH} = -12mA (-1H)$	2.4		
$I_{DD}$ (PD mode)	Pwr Dwn Supply Current	SEL1 = 0 (-1, -2, -3, -4, -1H); SEL2 = 0 (-6)		25.0	μA
$I_{DD}$	Supply Current	Unloaded outputs 100 MHz, Select inputs at $V_{DD}$ or GND		54.0	mA
				70.0 (-1H)	
		Unloaded outputs 66 MHz, CLKIN, except (-1H)		39.0	
		Unloaded outputs 33MHz, CLKIN, except (-1H)		20.0	

**AC Electrical Characteristics for Industrial Temperature Devices**

Parameters	Name	Test Conditions	Min.	Typ.	Max.	Units	
F <sub>O</sub>	Output Frequency	30pF load	10.0		100	MHz	
		20pF load, (-1H)			133		
		15pF load, (-1, -2, -3, -4, -6)					
t <sub>DC</sub>	Duty Cycle <sup>(1)</sup> (-1, -2, -3, -4, -6)	Measured at V <sub>DD</sub> /2, F <sub>OUT</sub> <66.67MHz 30pF load	40.0	50	60.0	%	
		Measured at V <sub>DD</sub> /2, F <sub>OUT</sub> <133MHz 15pF load					
		Measured at V <sub>DD</sub> /2, F <sub>OUT</sub> <45MHz 15pF load					
	Duty Cycle <sup>(1)</sup> (-1H)	Measured at V <sub>DD</sub> /2, F <sub>OUT</sub> <66.67MHz 30pF load	45.0		55.0		
		Measured at V <sub>DD</sub> /2, F <sub>OUT</sub> <133MHz 15pF load	40.0		60.0		
		Measured at V <sub>DD</sub> /2V, F <sub>OUT</sub> <45MHz 30pF load	45.0		55.0		
t <sub>R</sub>	Rise Time <sup>(1)</sup> (-1, -2, -3, -4,)	Measured between 0.8V and 2.0V, 30pF load			2.2	ns	
		Measured between 0.8V and 2.0V, 15pF load			1.50		
	Rise Time <sup>(1)</sup> (-1H)	Measured between 0.8V and 2.0V, 30pF load			1.50		
t <sub>F</sub>	Fall Time <sup>(1)</sup> (-1, -2, -3, -4,)	Measured between 0.8V and 2.0V, 30pF load			2.50		
		Measured between 0.8V and 2.0V, 15pF load			1.50		
	Fall Time <sup>(1)</sup> (-1H)	Measured between 0.8V and 2.0V, 30pF load			1.25		
t <sub>SK(O)</sub>	Output to Output Skew within same Bank (-1,-2,-3,-4,-6) <sup>(1)</sup>	All outputs equally loaded			200	ps	
	OUTA to OUTB Skew <sup>(1)</sup> (-1,-1H,-4)						
	OUTA to OUTB Skew <sup>(1)</sup> (-2,-3,-6)				400		
t <sub>0</sub>	Delay, CLKIN Rising Edge to FB_IN Rising Edge <sup>(1)</sup>	Measured at V <sub>DD</sub> /2		0	±200		
t <sub>SK(D)</sub>	Device-to-Device Skew <sup>(1)</sup>	Measured at V <sub>DD</sub> /2 on FB_IN pins of devices		0	600		
t <sub>SLEW</sub>	Output Slew Rate <sup>(1)</sup>	Measured between 0.8V & 2.0V on -1H device using Test Crt #2	1				V/ns
t <sub>JIT</sub>	Cycle-to-Cycle Jitter <sup>(1)</sup> (-1,-1H,-4)	Measured at 66.67 MHz, loaded 30pF load			200	ps	
		Measured at 133 MHz, loaded 15pF load			100		
	Cycle-to-Cycle Jitter <sup>(1)</sup> (-2,-3,-6)	Measured at 66.67 MHz, loaded 30pF load			400		
t <sub>LOCK</sub>	PLL Lock Time <sup>(1)</sup>	Stable power supply, valid clocks presented on CLKIN and FB_IN pins			1.0	ms	

**Notes:**

1. See Switching Waveforms on page 7.

**DC Electrical Characteristics for Commercial Temperature Devices**

Parameter	Description	Test Conditions	Min.	Max.	Units
V <sub>IL</sub>	Input LOW Voltage	—	—	0.8	V
V <sub>IH</sub>	Input HIGH Voltage	—	2.0	—	
I <sub>IL</sub>	Input LOW Current	V <sub>IN</sub> = 0V	—	50	μA
I <sub>IH</sub>	Input HIGH Current	V <sub>IN</sub> = V <sub>DD</sub>	—	100	
V <sub>OL</sub>	Output LOW Voltage	I <sub>OL</sub> = 8mA (-1, -2, -3, -4, -6); I <sub>OL</sub> = 12mA (-1H)	—	0.4	V
V <sub>OH</sub>	Output HIGH Voltage	I <sub>OH</sub> = -8mA (-1, -2, -3, -4, -6); I <sub>OH</sub> = -12mA (-1H)	2.4	—	
I <sub>DD</sub> (PD mode)	Power Down Supply Current	SEL1 = 0 (-1, -2, -3, -4, -1H); SEL2 = 0 (-6)	—	25	μA
I <sub>DD</sub>	Supply Current	Unloaded outputs, 66.67 MHz, Select inputs at V <sub>DD</sub> or GND	—	39	mA
I <sub>DD</sub>	Supply Current	Unloaded outputs 100 MHz Select Inputs @ V <sub>DD</sub> or GND	—	54	

**AC Electrical Characteristics for Commercial Temperature Device**

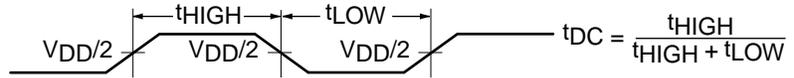
Parameters	Name	Test Conditions	Min.	Typ.	Max.	Units
F <sub>O</sub>	Output Frequency	30pF load	10		100	MHz
		20pF load, (-1H)			133	
		15pF load, (-1, -2, -3, -4, -6)				
t <sub>DC</sub>	Duty Cycle <sup>(1)</sup> (-1H)	Measured at V <sub>DD</sub> /2, for high drive output	45	50	55	%
	Duty Cycle (-1, -2, -3, -4, -6)	Measured at V <sub>DD</sub> /2, for normal drive output	40	50	60	
t <sub>R</sub>	Rise Time <sup>(1)</sup> @30pF	Measured between 0.8V and 2.0V			2.2	ns
	Rise Time <sup>(1)</sup> @15pF				1.5	
	Rise Time <sup>(1)</sup> @30pF (-1H)				1.5	
t <sub>F</sub>	Fall Time <sup>(1)</sup> @30pF				2.2	
	Fall Time <sup>(1)</sup> @15pF				1.5	
	Fall Time <sup>(1)</sup> @30pF (-1H)				1.25	
t <sub>SK(O)</sub>	Output to Output Skew <sup>(1)</sup> within same bank (-1, -1H, -2, -3, -4, -6)	All outputs equally loaded, V <sub>DD</sub> /2			200	ps
	OUTA to OUTB Skew <sup>(1)</sup> (-1, -1H, -4)	All outputs equally loaded, V <sub>DD</sub> /2			200	
	OUTA to OUTB Skew <sup>(1)</sup> (-2, -3, -6)	All outputs equally loaded, V <sub>DD</sub> /2			400	
t <sub>0</sub>	Input to Output Delay, CLKIN Rising Edge to FB_IN Rising Edge <sup>(1)</sup>	Measured at V <sub>DD</sub> /2		0	±200	
t <sub>SK(D)</sub>	Device to Device Skew <sup>(1)</sup>	Measured at V <sub>DD</sub> /2 on FB_IN pins of devices		0	600	
t <sub>SLEW</sub>	Output Slew Rate <sup>(1)</sup>	Measured between 0.8V and 2.0V on -1H device using Test Circuit #2	1			V/ns
t <sub>JIT</sub>	Cycle-to-Cycle Jitter <sup>(1)</sup> (-1, -1H, -4)	Measured at 66.67 MHz, loaded 30pF outputs			200	ps
		Measured at 133 MHz, loaded 15pF outputs			100	
	Cycle-to-Cycle Jitter <sup>(1)</sup> (-2, -3, -6)	Measured at 66.7 MHz, loaded 30pF outputs			400	
t <sub>LOCK</sub>	PLL Lock Time <sup>(1)</sup>	Stable power supply, valid clocks presented on CLKIN and FB_IN pins			1.0	ms

**Notes:**

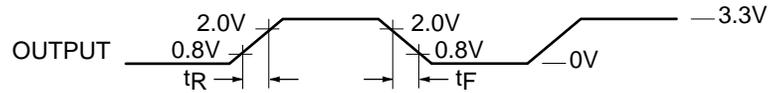
1. See Switching Waveforms on page 7.

### Switching Waveforms

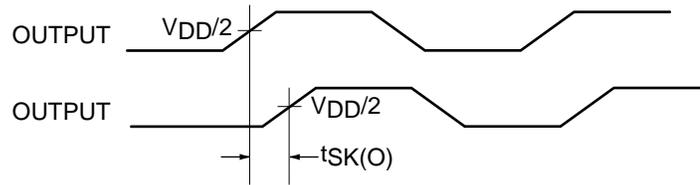
Duty Cycle Timing



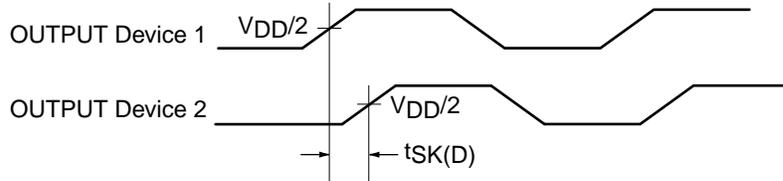
All Outputs Rise/Fall Time



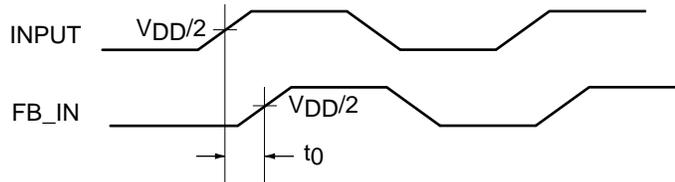
Output-Output Skew



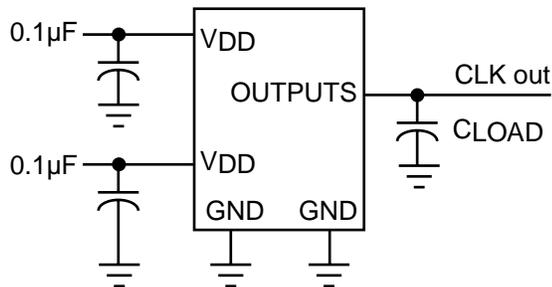
Device-Device Skew



Input-Output Propagation Delay

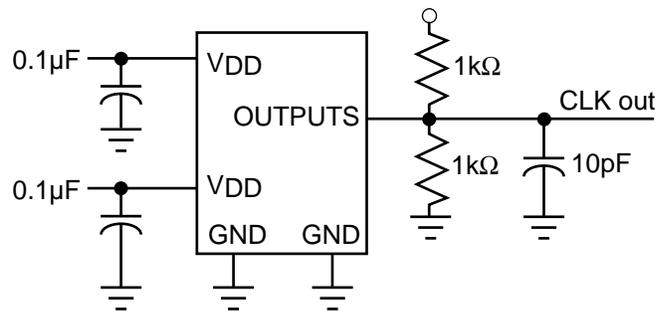


Test Circuit 1



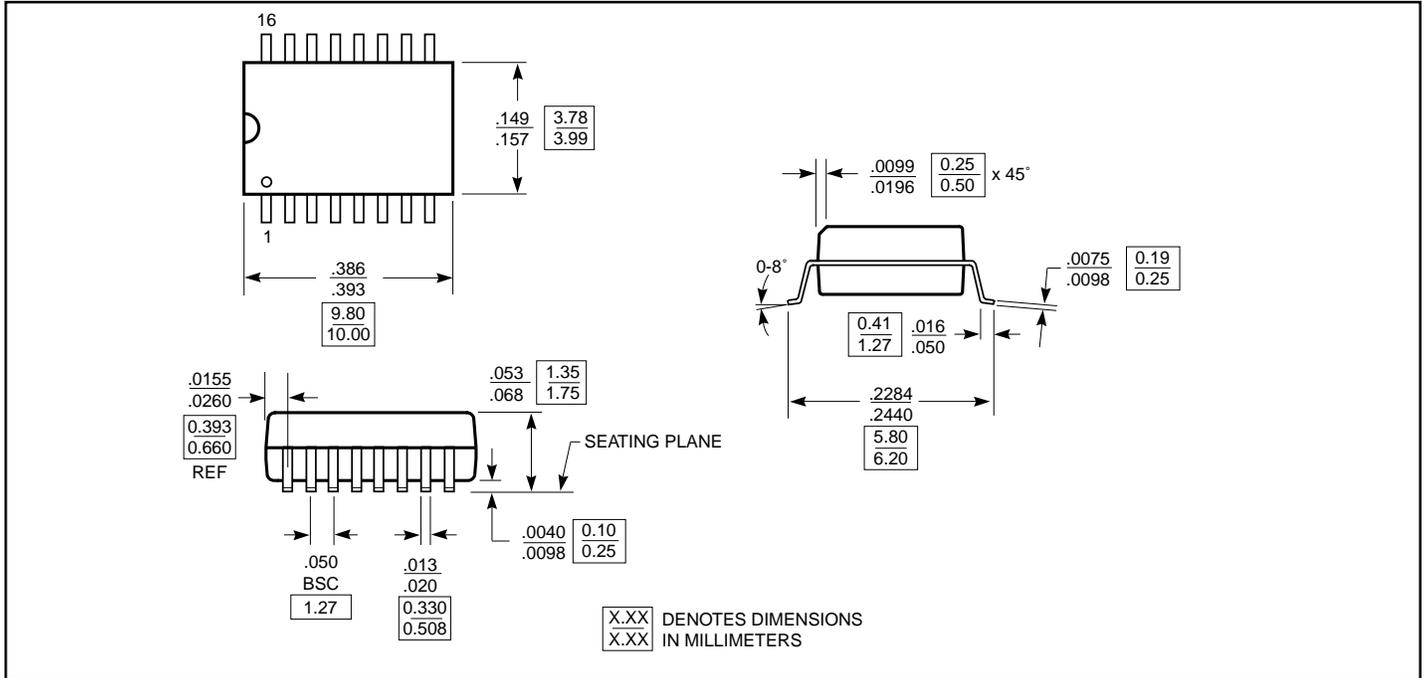
Test Circuit for all parameters except  $t_{SLEW}$

Test Circuit 2

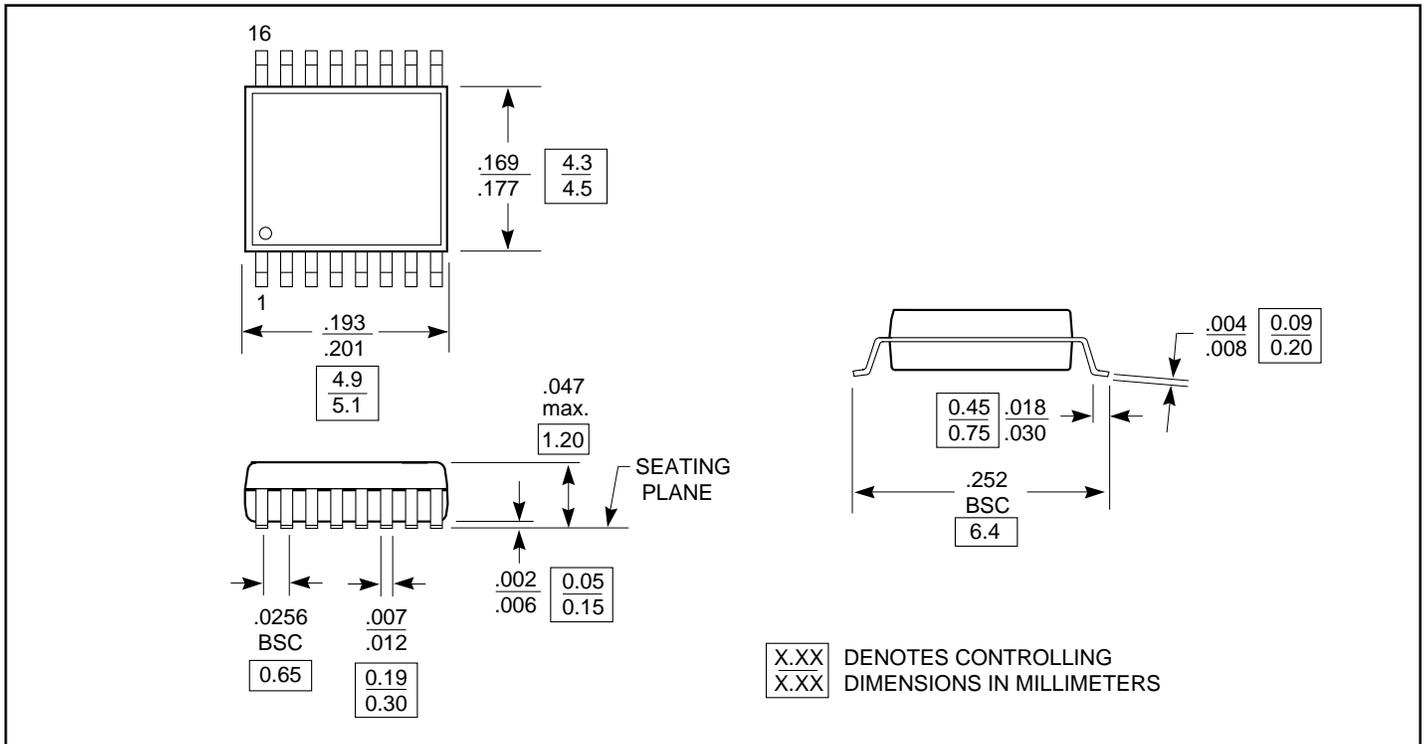


Test Circuit for  $t_{SLEW}$ , Output slew rate on -1H device

### 16-Pin SOIC (W) Package



### 16-Pin TSSOP (L) Package



Note: Controlling dimensions in millimeters. Ref: JEDEC MS - 012 AC

**Ordering Information (Commercial Temperature Device)**

Ordering Code	Package Name	Package Type	Operating Range
PI6C2308-1W	W16	16-pin 150-mil SOIC	Commercial
PI6C2308-1HW			
PI6C2308-2W			
PI6C2308-3W			
PI6C2308-4W			
PI6C2308-6W			
PI6C2308-1L	L16	16-pin TSSOP	Commercial
PI6C2308-1HL			

**Ordering Information (Industrial Temperature Device)**

Ordering Code	Package Name	Package Type	Operating Range
PI6C2308-1WI	W16	16-pin 150-mil SOIC	Industrial
PI6C2308-1HWI			
PI6C2308-2WI			
PI6C2308-3WI			
PI6C2308-4WI			
PI6C2308-6WI			
PI6C2308-1LI	L16	16-pin TSSOP	Industrial
PI6C2308-1HLI			